

Form PTO 1449 (Modified)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY DOCKET NO. 212881US2	SERIAL NO. NEW APPLICATION
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT	Eiji YOSHIDA
		FILING DATE HEREWITH	GROUP

1033 US PTQ 209/921104
08/17/01

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
AA							
AB							
AC							
AD							
AE							
AF							
AG							
AH							
AI							
AJ							
AK							
AL							
AM							
AN							

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES	NO
AO						
AP						
AQ						
AR						
AS						
AT						
AU						
AV						

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

<i>JP</i>	AW	Mario PANICCIA, et al., "NOVEL OPTICAL PROBING TECHNIQUE FOR FLIP CHIP PACKAGED MICROPROCESSORS", INTERNATIONAL TEST CONFERENCE 1998, IEEE, pp 740-747
<i>JP</i>	AX	T.M. EILES, et al., "OPTICAL INTERFEROMETRIC PROBING OF ADVANCED MICROPROCESSORS", INTERNATIONAL TEST CONFERENCE 2000, 5 pages
	AY	
	AZ	

Examiner *J. MONDT*Date Considered *May 9 '02*

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.